

30V N-Ch Power MOSFET

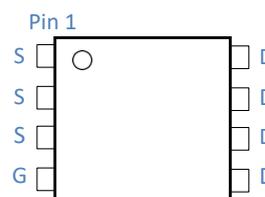
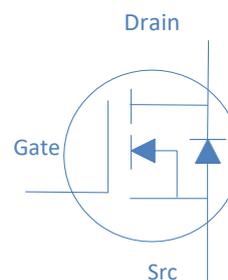
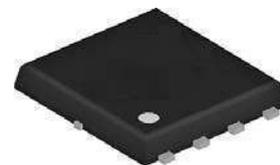
Features:

- ◇ Optimized for high speed switching, Logic Level
- ◇ Enhanced Body diode dv/dt capability
- ◇ Enhanced Avalanche Ruggedness
- ◇ 100% UIS Tested, 100% Rg Tested
- ◇ Lead Free, Halogen Free

Application:

- ◇ Synchronous Rectification in SMPS
- ◇ Hard Switching and High Speed Circuit
- ◇ Power Tools
- ◇ UPS
- ◇ Motor Control

DFN5x6



| Part Number | Package | Marking |
|--------------|---------|-----------|
| KPRTN010N03P | DFN5x6 | TN010N03P |

| | | |
|--------------------------------|-----|------------|
| V_{DS} | 30 | V |
| $R_{DS(on),max}$ $V_{GS}=10V$ | 1.0 | m Ω |
| $R_{DS(on),max}$ $V_{GS}=4.5V$ | 1.4 | m Ω |
| I_D | 254 | A |

Absolute Maximum Ratings at $T_J=25^{\circ}C$ (unless otherwise specified)

| Parameter | Symbol | Conditions | Value | Unit |
|--|----------------|----------------------------|------------|-------------|
| Continuous Drain Current (Silicon Limited) | I_D | $T_C=25^{\circ}C$ | 254 | A |
| | | $T_C=100^{\circ}C$ | 160 | |
| Drain to Source Voltage | V_{DS} | - | 30 | V |
| Gate to Source Voltage | V_{GS} | - | ± 20 | V |
| Pulsed Drain Current | I_{DM} | - | 400 | A |
| Avalanche Energy, Single Pulse | E_{AS} | $L=0.3mH, T_C=25^{\circ}C$ | 375 | mJ |
| Power Dissipation | P_D | $T_C=25^{\circ}C$ | 96 | W |
| Operating and Storage Temperature | T_J, T_{stg} | - | -55 to 150 | $^{\circ}C$ |

Absolute Maximum Ratings

| Parameter | Symbol | Max | Unit |
|-------------------------------------|-----------------|-----|---------------|
| Thermal Resistance Junction-Case | $R_{\theta JC}$ | 1.3 | $^{\circ}C/W$ |
| Thermal Resistance Junction-Ambient | $R_{\theta JA}$ | 50 | $^{\circ}C/W$ |

Electrical Characteristics at $T_j=25^\circ\text{C}$ (unless otherwise specified)

Static Characteristics

| Parameter | Symbol | Conditions | Value | | | Unit |
|-----------------------------------|---------------|---|-------|------|-----------|-----------|
| | | | min | typ | max | |
| Drain to Source Breakdown Voltage | $V_{(BR)DSS}$ | $V_{GS}=0V, I_D=250\mu A$ | 30 | - | - | V |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{GS}=V_{DS}, I_D=250\mu A$ | 1 | 1.5 | 2 | |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{GS}=0V, V_{DS}=24V, T_j=25^\circ\text{C}$ | - | - | 1 | μA |
| Gate to Source Leakage Current | I_{GSS} | $V_{GS}=\pm 20V, V_{DS}=0V$ | - | - | ± 100 | nA |
| Drain to Source on Resistance | $R_{DS(on)}$ | $V_{GS}=10V, I_D=20A$ | - | 0.85 | 1 | $m\Omega$ |
| | | $V_{GS}=4.5V, I_D=15A$ | - | 1.1 | 1.4 | $m\Omega$ |
| Transconductance | g_{fs} | $V_{DS}=5V, I_D=10A$ | - | 54 | - | S |
| Gate Resistance | R_G | $V_{GS}=0V, V_{DS}$ Open, $f=1\text{MHz}$ | - | 4 | - | Ω |

Dynamic Characteristics

| | | | | | | |
|-------------------------------|--------------|--|---|-------|---|----|
| Input Capacitance | C_{iss} | $V_{GS}=0V, V_{DS}=15V, f=1\text{MHz}$ | - | 6545 | - | pF |
| Output Capacitance | C_{oss} | | - | 996 | - | |
| Reverse Transfer Capacitance | C_{rss} | | - | 772 | - | |
| Total Gate Charge (10V) | $Q_g(10V)$ | $V_{DD}=15V, I_D=20A, V_{GS}=10V$ | - | 175.7 | - | nC |
| Total Gate Charge (4.5V) | $Q_g(4.5V)$ | | - | 84 | - | |
| Gate to Source Charge | Q_{gs} | | - | 30.6 | - | |
| Gate to Drain (Miller) Charge | Q_{gd} | | - | 30 | - | |
| Turn on Delay Time | $t_{d(on)}$ | $V_{DD}=15V, I_D=1A, V_{GS}=10V, R_G=6\Omega,$ | - | 14 | - | ns |
| Rise time | t_r | | - | 24.1 | - | |
| Turn off Delay Time | $t_{d(off)}$ | | - | 330 | - | |
| Fall Time | t_f | | - | 133.5 | - | |

Reverse Diode Characteristics

| | | | | | | |
|-------------------------|----------|--|---|------|-----|----|
| Diode Forward Voltage | V_{SD} | $V_{GS}=0V, I_F=10A$ | - | 0.7 | 1.1 | V |
| Reverse Recovery Time | t_{rr} | $I_F=10A, V_R=15V, dI_F/dt=100A/\mu s$ | - | 36.9 | - | ns |
| Reverse Recovery Charge | Q_{rr} | | - | 35.6 | - | nC |

Fig 1. Typical Output Characteristics

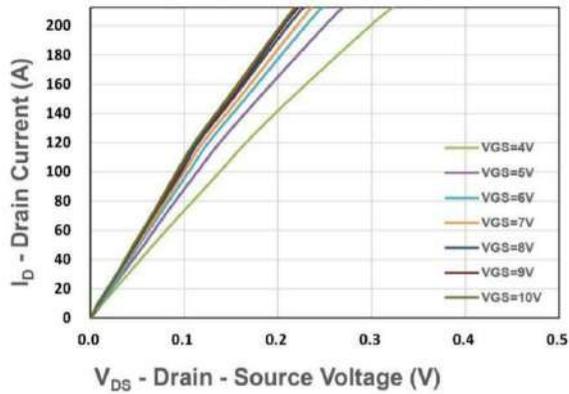


Figure 2. On-Resistance vs. Gate-Source Voltage

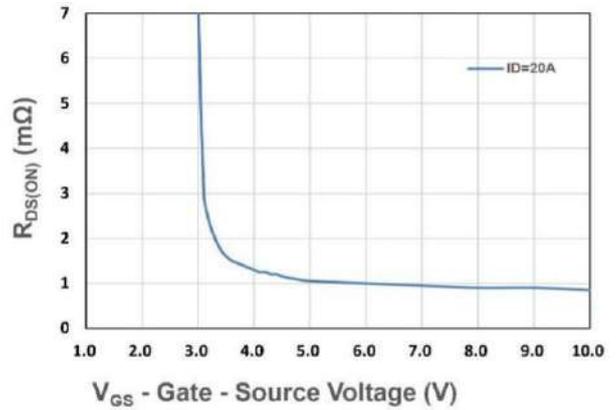


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

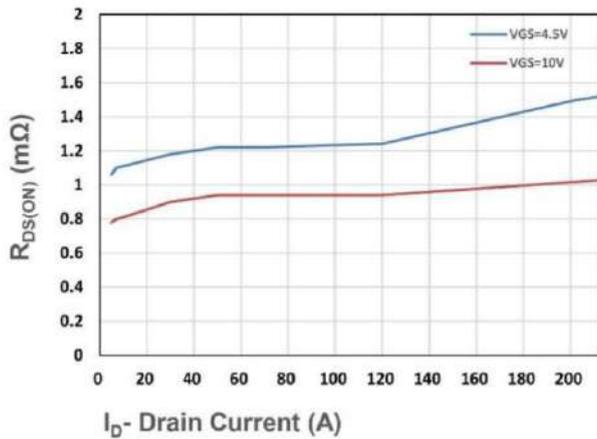


Figure 4. Normalized On-Resistance vs. Junction Temperature

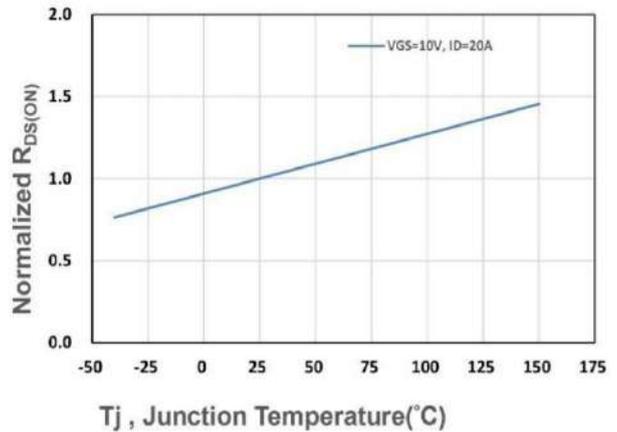


Figure 5. Normalized Threshold Voltage VS Junction Temperature

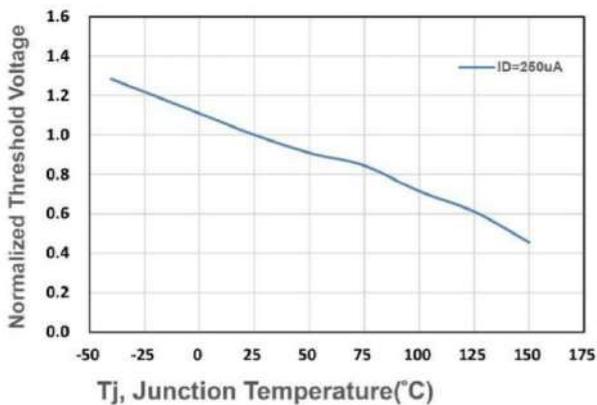


Figure 6. Typical Source-Drain Diode Forward Voltage

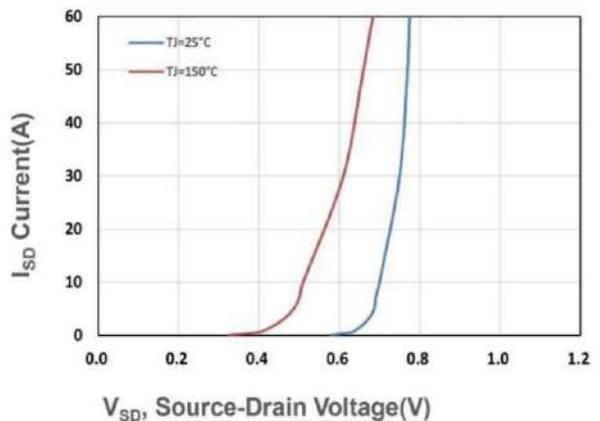


Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

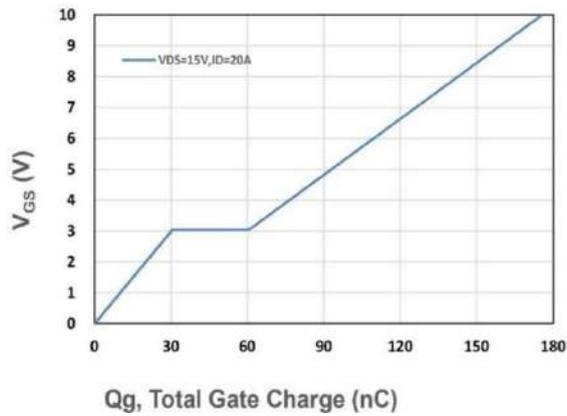


Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

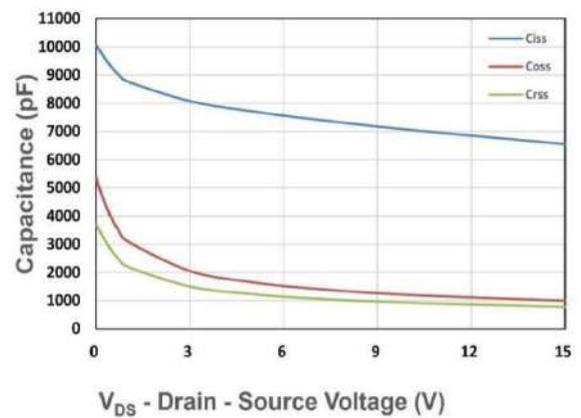


Figure 9. Maximum Safe Operating Area

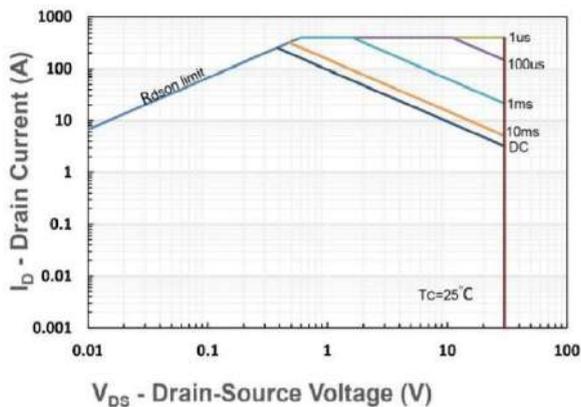


Figure 10. Maximun Drain Current vs. Case Temperature

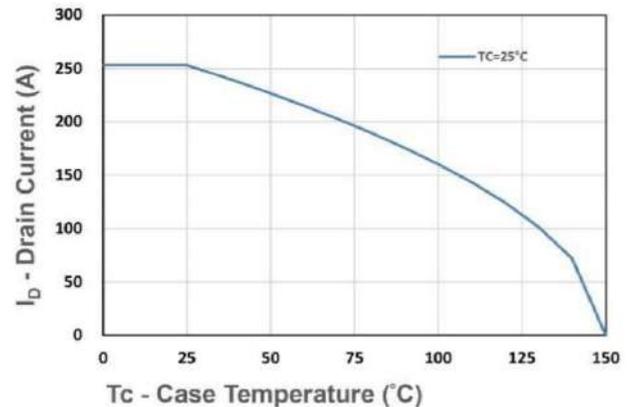
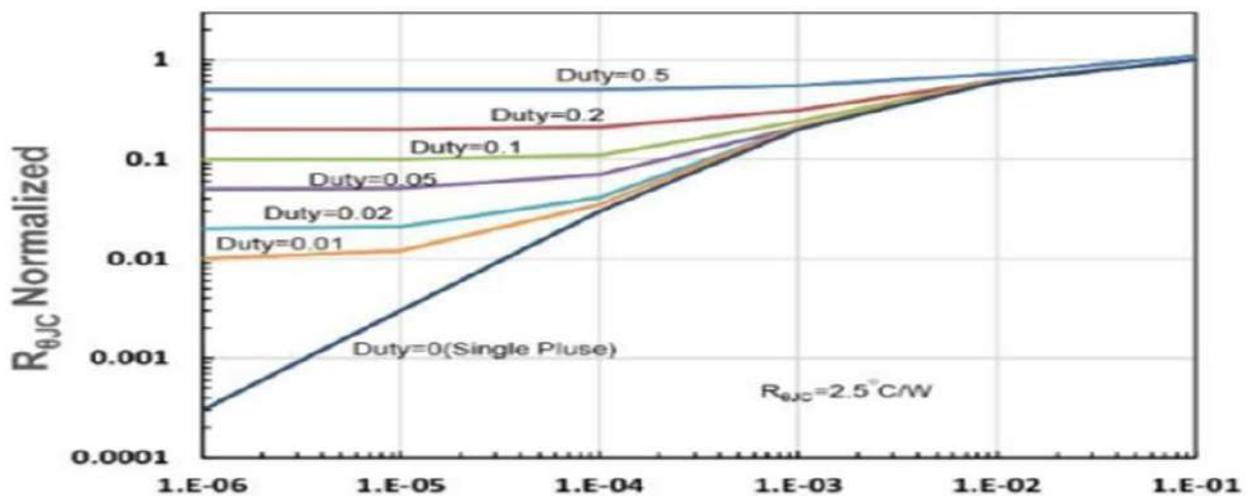
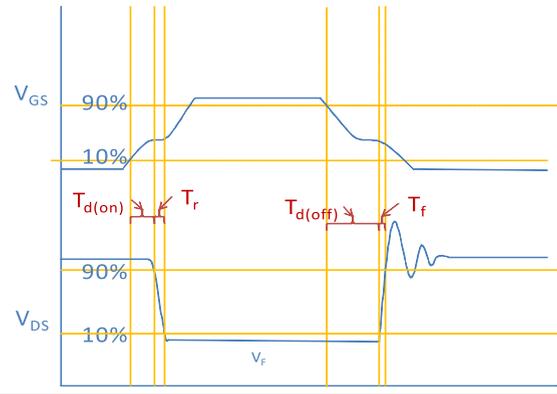
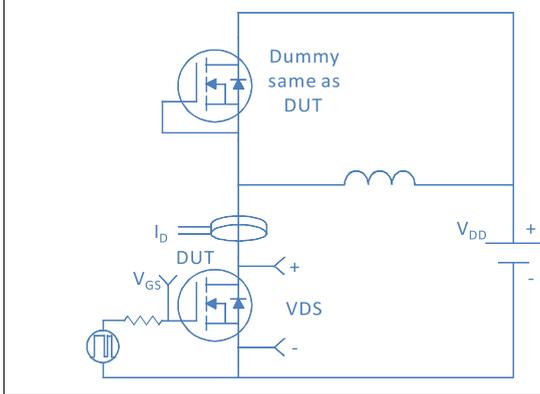


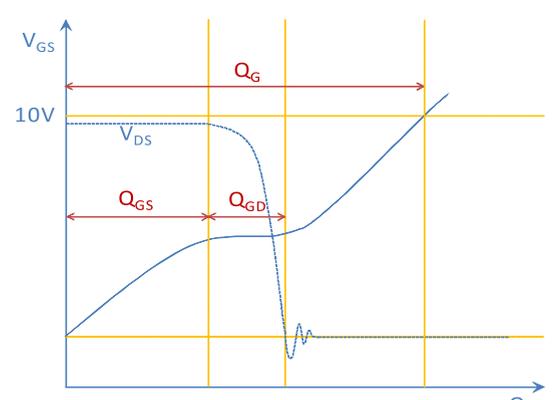
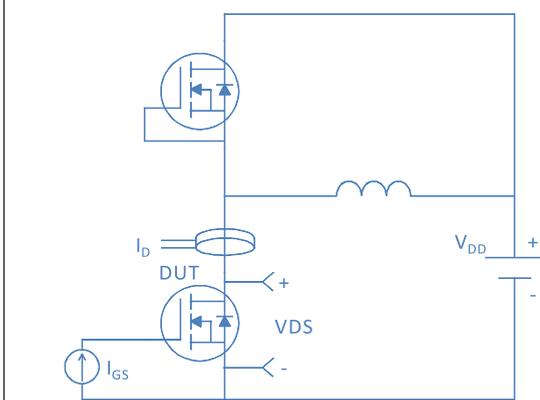
Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Case



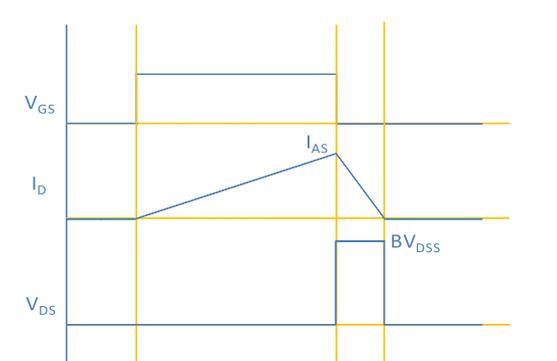
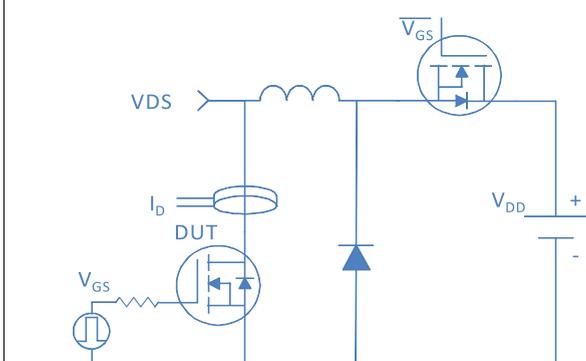
Inductive switching Test



Gate Charge Test



Uclamped Inductive Switching (UIS) Test



Diode Recovery Test

